

September 1998

#### 54ACT112

### **Dual JK Negative Edge-Triggered Flip-Flop**

#### **General Description**

The 'ACT112 contains two independent, high-speed JK flip-flops with Direct Set and Clear inputs. Synchronous state changes are initiated by the falling edge of the clock. Triggering occurs at a voltage level of the clock and is not directly related to the transition time. The J and K inputs can change when the clock is in either state without affecting the flip-flop, provided that they are in the desired state during the recommended setup and hold times relative to the falling edge of the clock. A LOW signal on  $\overline{S}_D$  or  $\overline{C}_D$  prevents clocking and forces Q or  $\overline{Q}$  HIGH, respectively. Simultaneous LOW signals on  $\overline{S}_D$  and  $\overline{C}_D$  force both Q and  $\overline{Q}$  HIGH.

Asynchronous Inputs:

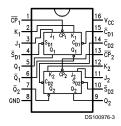
LOW input to  $\overline{S}_D$  sets Q to HIGH level LOW input to  $\overline{C}_D$  sets Q to LOW level Clear and Set are independent of clock Simultaneous LOW on  $\overline{C}_D$  and  $\overline{S}_D$  makes both Q and  $\overline{Q}$  HIGH

#### **Features**

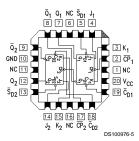
- 'ACT112 has TTL-compatible inputs
- Outputs source/sink 24 mA
- Standard Microcircuit Drawing (SMD) 5962-8995001

#### **Connection Diagram**

# Pin Assigment for DIP and Flatpack



## Pin Assigment for LCC

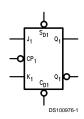


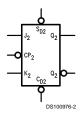
#### **Pin Descriptions**

Pin Names	Description
$J_1$ , $J_2$ , $K_1$ , $K_2$ $\overline{CP}_1$ , $\overline{CP}_2$	Data Inputs
$\overline{CP}_1$ , $\overline{CP}_2$	Clock Pulse Inputs
	(Active Falling Edge)
$\overline{C}_{D1}, \overline{C}_{D2}$	Direct Clear Inputs (Active LOW)
$\overline{S}_{D1}$ , $\overline{S}_{D2}$	Direct Set Inputs (Active LOW)
$Q_1, Q_2, \overline{Q}_1, \overline{Q}_2$	Outputs

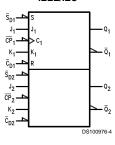
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### Logic Symbols





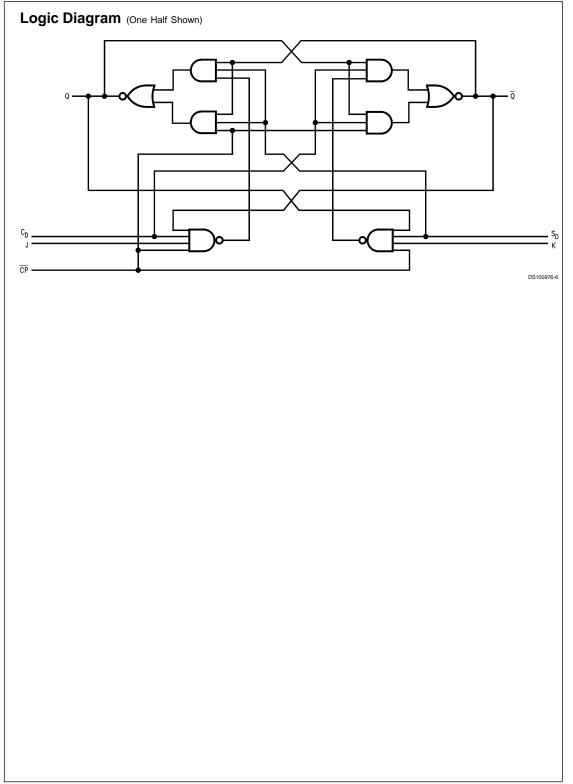
#### IEEE/IEC



### **Truth Table**

Inputs				Out	puts	
$\overline{S}_{D}$	$\overline{C}_{D}$	CP	J	K	Q	Q
L	Н	Χ	Χ	Χ	Н	L
Н	L	Χ	Χ	Χ	L	н
L	L	Χ	Χ	Χ	Н	Н
Н	Н	M	h	h	$\overline{Q}_{o}$	$Q_{o}$
Н	Н	M	1	h	L	Н
Н	Н	M	h	1	Н	L
Н	Н	М	I	I	Qo	$\overline{Q}_{o}$

 $\label{eq:local_control_control_control} H \ (h) = HIGH \ Voltage \ Level \\ L \ (i) = LOW \ Voltage \ Level \\ X = Immaterial \\ M = HIGH-to-LOW \ Clock \ Transition \\ Q_0 \ (\overline{Q}_0) = Before \ HIGH-to-LOW \ Transition \ of \ Clock \\ Lower \ case \ letters \ indicate \ the \ state \ of \ the \ referenced \ input \ or \ output \ one \ setup \ time \ prior \ to \ the \ HIGH-to-LOW \ clock \ transition.$ 



#### **Absolute Maximum Ratings** (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Supply Voltage (V<sub>CC</sub>) -0.5V to +7.0V

DC Input Diode Current (IIK)

 $V_1 = -0.5V$ -20 mA  $V_I = V_{CC} + 0.5V$ +20 mA

DC Input Voltage (V<sub>I</sub>) –0.5V to  $V_{\rm CC}$  + 0.5V

DC Output Diode Current ( $I_{OK}$ )

 $V_{O} = -0.5V$ -20 mA  $V_O = V_{CC} + O.5$ +20 mA -0.5V to  $V_{\rm CC}$  +0.5V

DC Output Voltage (Vo) DC Output Source

or Sink Current ( $I_{\rm O}$ ) ±50 mA

DC V<sub>CC</sub> or Ground Current

per Output Pin (I<sub>CC</sub> or I<sub>GND</sub>) ±50 mA Storage Temperature (T<sub>STG</sub>)

-65°C to +150°C

Junction Temperature (T<sub>J</sub>)

175°C

#### **Recommended Operating Conditions**

4.5V to 5.5V Supply Voltage (V<sub>CC</sub>) 0V to  $V_{\rm CC}$ Input Voltage (V<sub>I</sub>) 0V to  $V_{\rm CC}$ Output Voltage (V<sub>O</sub>) Operating Temperature (T<sub>A</sub>) -55°C to +125°C Minimum Input Edge Rate  $(\Delta V/\Delta t)$ 125 mV/ns

V<sub>IN</sub> from 0.8V to 2.0V

V<sub>CC</sub> @ 4.5V, 5.5V

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. Fairchild does not recommend operation of FACT™ circuits outside databook specifications.

#### DC Characteristics for 'ACT Family Devices

Symbol	Parameter	V <sub>CC</sub>	T <sub>A</sub> = -55°C to +125°C	Units	Conditions
		(V)	Guaranteed Limits		
V <sub>IH</sub>	Minimum High Level	4.5	2.0	V	V <sub>OUT</sub> = 0.1V
	Input Voltage	5.5	2.0		or V <sub>CC</sub> – 0.1V
V <sub>IL</sub>	Maximum Low Level	4.5	0.8	V	V <sub>OUT</sub> = 0.1V
	Input Voltage	5.5	0.8		or V <sub>CC</sub> – 0.1V
V <sub>OH</sub>	Minimum High Level	4.5	4.4	V	I <sub>OUT</sub> = -50 μA
	Output Voltage	5.5	5.4		
					V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub>
		4.5	3.70	V	I <sub>OH</sub> = -24 mA
		5.5	4.70		I <sub>OH</sub> = -24 mA
					(Note 2)
V <sub>OL</sub>	Maximum Low Level	4.5	0.1	V	I <sub>OUT</sub> = 50 μA
	Output Voltage	5.5	0.1		
					V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub>
		4.5	0.5	V	I <sub>OL</sub> = 24 MA
		5.5	0.5		I <sub>OL</sub> = 24 mA
					(Note 2)
I <sub>IN</sub>	Maximum Input Leakage Current	5.5	± 1.0	μА	V <sub>I</sub> = V <sub>CC</sub> , GND
I <sub>CCT</sub>	Maximum I <sub>CC</sub> /Input	5.5	1.6	mA	$V_{I} = V_{CC} - 2.1V$
I <sub>OLD</sub>	Minimum Dynamic	5.5	50	mA	V <sub>OLD</sub> = 1.65V Max
I <sub>OHD</sub>	Output Current(Note 3)	5.5	-50	mA	V <sub>OHD</sub> = 3.85V Min
I <sub>CC</sub>	Maximum Quiescent Supply Current	5.5	80.0	μА	V <sub>IN</sub> = V <sub>CC</sub> or GND

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time

Symbol	Parameter	V <sub>CC</sub> (V) (Note 4)	$T_A = -55^{\circ}C$ to +125°C $C_L = 50 \text{ pF}$		Units
			f <sub>max</sub>	Maximum Clock	5.0
Frequency					
t <sub>PLH</sub>	Propagation Delay	5.0	1.0	14.0	ns
	$CP_n$ to $Q_n$ or $\overline{Q}_n$				
t <sub>PHL</sub>	Propagation Delay	5.0	1.0	14.0	ns
	$CP_n$ to $Q_n$ or $\overline{Q}_n$				
t <sub>PLH</sub>	Propagation Delay	5.0	1.0	13.5	ns
	$\overline{C}_{Dn}$ or $\overline{S}_{Dn}$ to $Q_n$ or $\overline{Q}_n$				
t <sub>PHL</sub>	Propagation Delay	5.0	1.0	13.5	ns
	$\overline{C}_{Dn}$ or $\overline{S}_{Dn}$ to $Q_n$ or $\overline{Q}_n$				

Note 4: Voltage Range 5.0 is 5.0V ±0.5V

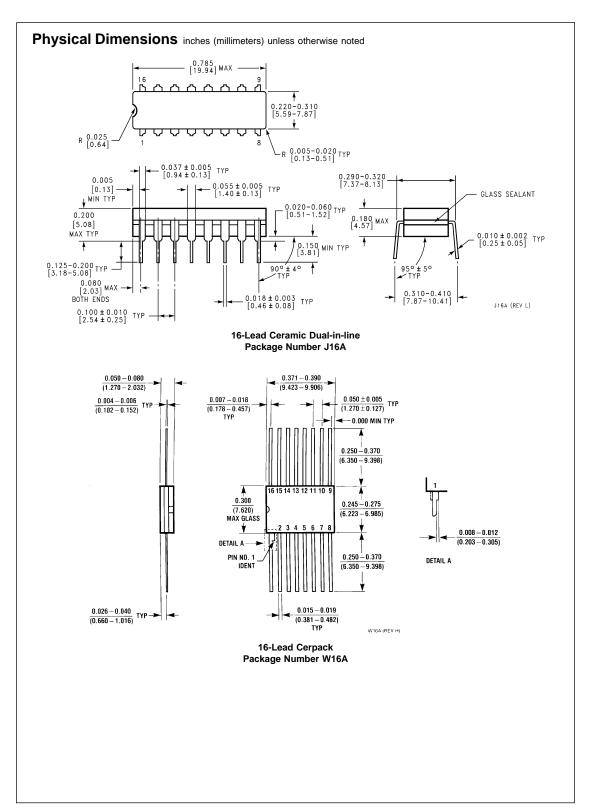
# **AC Operating Requirements:**

Symbol	Parameter	V <sub>cc</sub> (V)	T <sub>A</sub> = -55°C to +125°C C <sub>L</sub> = 50 pF	Units
		(Note 5)	Guaranteed Minimum	
t <sub>S</sub>	Setup Time, HIGH or LOW	5.0	8.0	ns
	$J_n$ or $\overline{K}_n$ to $CP_n$			
t <sub>H</sub>	Hold Time, HIGH or LOW	5.0	1.5	ns
	$J_n$ or $\overline{K}_n$ to $CP_n$			
t <sub>W</sub>	Pulse Width	5.0	5.0	ns
	$CP_n$ or $\overline{C}_{Dn}$ or $\overline{S}_{Dn}$			
t <sub>rec</sub>	Recovery Time	5.0	3.0	ns
	$\overline{C}_{Dn}$ or $\overline{S}_{Dn}$ to $CP_n$			

Note 5: Voltage Range 5.0 is 5.0V ±0.5V

### Capacitance

Symbol	Parameter	Max	Units	Conditions
C <sub>IN</sub>	Input Capacitance	10.0	pF	V <sub>CC</sub> = OPEN
Cpp	Power Dissipation Capacitance	60	pF	V <sub>CC</sub> = 5.0V



#### Physical Dimensions inches (millimeters) unless otherwise noted (Continued) $\boldsymbol{0.200 \pm 0.005}$ $(5.080 \pm 0.127)$ TYP $\frac{0.015\pm0.010}{(0.381\pm0.254)}$ $\boldsymbol{0.350 \pm 0.008}$ 0.015 0.007 - 0.0110.063 - 0.075 $(8.890 \pm 0.203)$ (0.178 - 0.279)(1.600 - 1.905)R TYP $\frac{0.022 - 0.028}{(0.559 - 0.711)}$ 0.077 - 0.093-PIN #1 $\overline{(1.959 - 2.362)}$ INDEX $\frac{0.045 - 0.055}{(1.143 - 1.397)}$

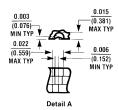
**Bottom View** 

0.067 - 0.083

(1.702 - 2.108)

 $\begin{array}{c} \underline{0.040 \pm 0.010} \\ \hline (1.016 \pm 0.254) \\ 3 \text{ PLCS} \end{array}$ 

45° ×



- DETAIL A

Side View

E20A (REV DI

0.045 - 0.055 (1.143 - 1.397)

TYP

20-Lead Ceramic Leadless Chip Carrier Package Number E20A

#### LIFE SUPPORT POLICY

Top View

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